

N-CHANNEL SILICON POWER MOS-FET

FAP-III SERIES

Features

- High current
- Low on-resistance
- No secondary breakdown
- Low driving power
- High forward Transconductance
- Avalanche-proof

Applications

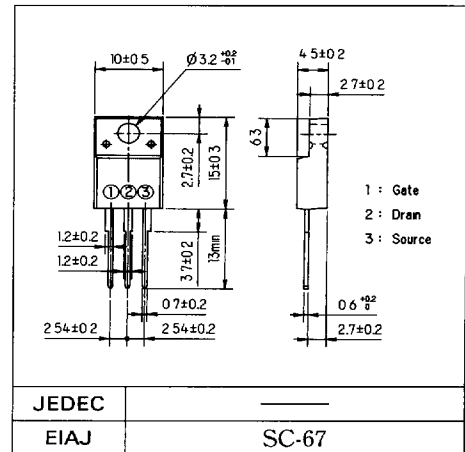
- Motor controllers
- General purpose power amplifier
- DC-DC converters

Max. Ratings and Characteristics

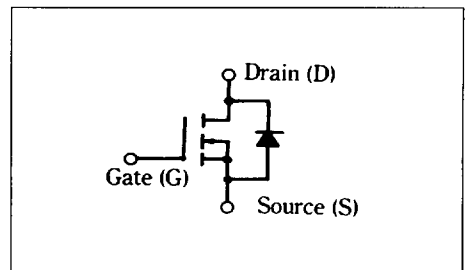
- Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$) (unless otherwise specified)

Items	Symbols	Ratings	Units
Drain-source voltage	V_{DS}	150	V
Drain-gate voltage ($R_{GS} = 20\text{K}\Omega$)	V_{DGR}	150	V
Continuous drain current	I_D	20	A
Pulsed drain current	$I_{D(puls)}$	80	A
Gate-source voltage	V_{GS}	± 20	V
Max. power dissipation	P_D	50	W
Operating and storage temperature range	T_{ch}	150	$^\circ\text{C}$
	T_{stg}	$-55 \sim +150$	$^\circ\text{C}$

Outline Drawings



Equivalent Circuit Schematic



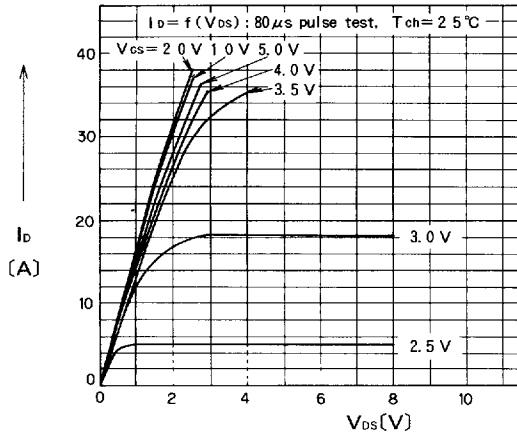
- Electrical Characteristics ($T_c = 25^\circ\text{C}$) (unless otherwise specified)

Items	Symbols	Test Conditions	Min.	Typ.	Max.	Units
Drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D = 1\text{mA}$ $V_{GS} = 0\text{V}$	150			V
Gate threshold voltage	$V_{GS(th)}$	$I_D = 1\text{mA}$ $V_{DS} = V_{GS}$	1.0	1.5	2.5	V
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 150\text{V}$ $V_{GS} = 0\text{V}$	$T_{ch} = 25^\circ\text{C}$	10	500	μA
			$T_{ch} = 125^\circ\text{C}$	0.2	1.0	mA
Gate-source leakage current	I_{GSS}	$V_{GS} = \pm 20\text{V}$ $V_{DS} = 0\text{V}$		10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$I_D = 10\text{A}$	$V_{GS} = 4\text{V}$	0.065	0.100	Ω
			$V_{GS} = 10\text{V}$	0.055	0.080	Ω
Forward transconductance	g_{fs}	$I_D = 10\text{A}$ $V_{DS} = 25\text{V}$	10	20		S
Input capacitance	C_{iss}	$V_{DS} = 25\text{V}$ $V_{GS} = 0\text{V}$ $f = 1\text{MHz}$		2300	3450	pF
Output capacitance	C_{oss}			330	500	
Reverse transfer capacitance	C_{rss}			150	230	
Turn-on time t_{on} ($t_{on} = t_{d(on)} + t_r$)	$t_{d(on)}$ t_r	$V_{CC} = 30\text{V}$ $I_D = 20\text{A}$ $V_{GS} = 10\text{V}$ $R_{GS} = 25\Omega$		15	25	ns
				20	30	
Turn-off time t_{off} ($t_{off} = t_{d(off)} + t_f$)	$t_{d(off)}$ t_f			450	700	
				100	150	
Avalanche capability	I_{AV}	$L = 100\mu\text{H}$ $T_{ch} = 25^\circ\text{C}$	20			A
Continuous reverse drain current	I_{DR}				20	A
Pulsed reverse drain current	I_{DRM}				80	A
Diode forward on-voltage	V_{SD}	$I_F = 2 \times I_{DR}$ $V_{GS} = 0\text{V}$ $T_{ch} = 25^\circ\text{C}$		1.00	1.50	V
Reverse recovery time	t_{rr}	$I_F = I_{DR}$ $V_{GS} = 0\text{V}$		125		ns
Reverse recovery charge	Q_{rr}	$-dI_F/dt = 100\text{A}/\mu\text{s}$ $T_{ch} = 25^\circ\text{C}$		0.6		μC

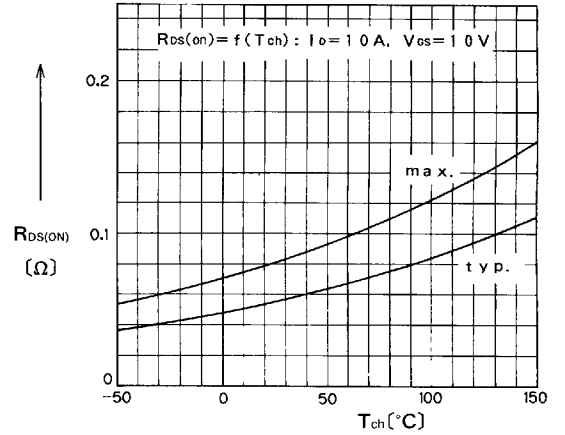
Thermal Characteristics

Items	Symbols	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	$R_{th(ch-a)}$	channel to air			62.5	$^\circ\text{C}/\text{W}$
	$R_{th(ch-c)}$	channel to case			2.5	$^\circ\text{C}/\text{W}$

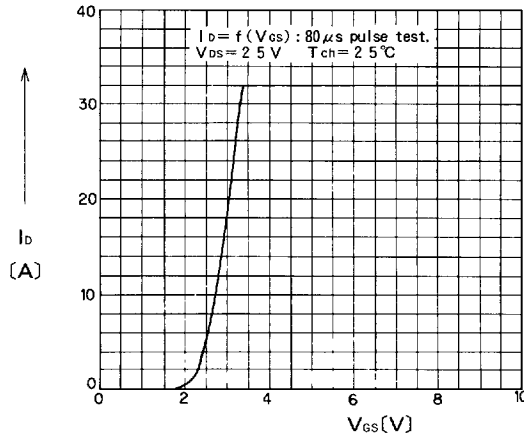
■ Characteristics



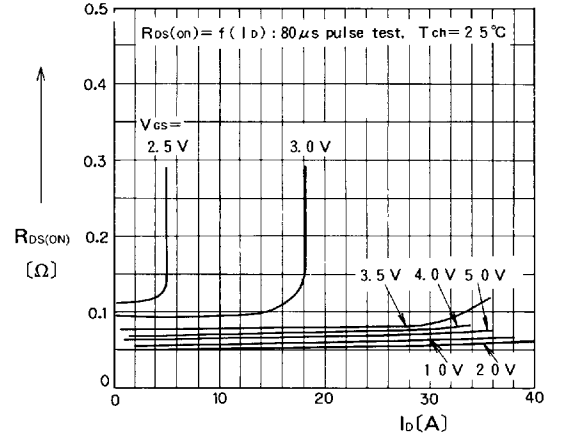
Typical Output Characteristics



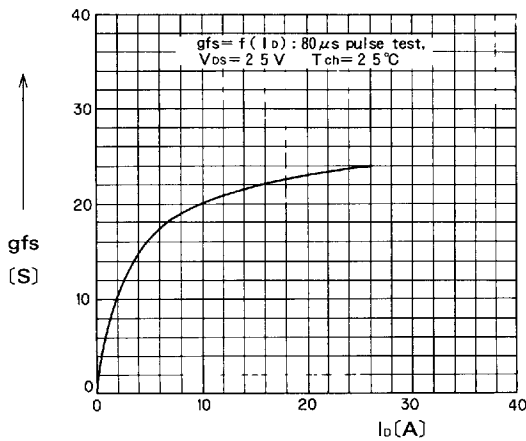
Drain-Source on-State Resistance vs. T_{ch}



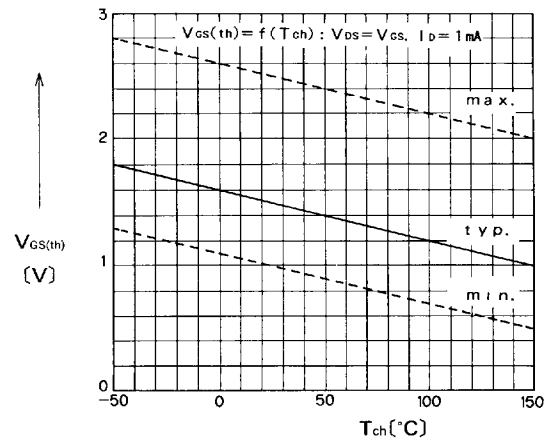
Typical Transfer Characteristics



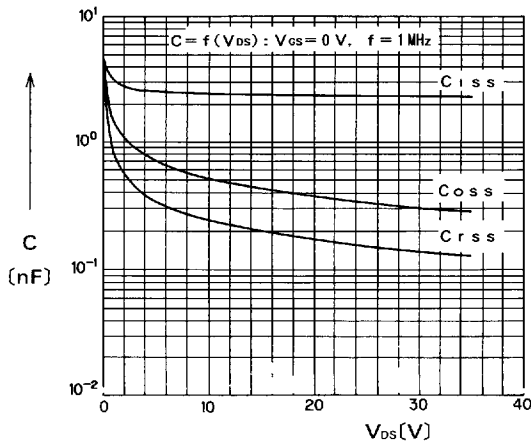
Typical Drain-Source on-State Resistance vs. I_D



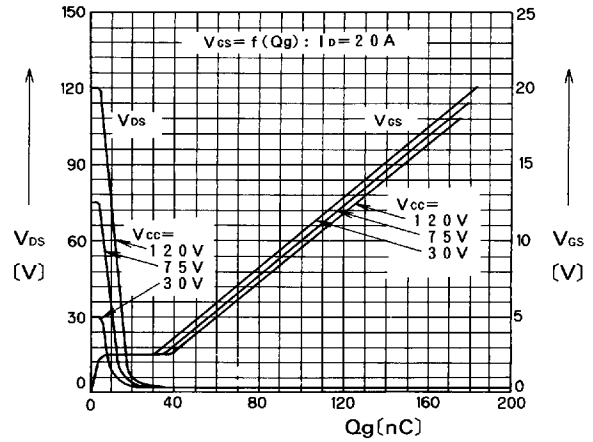
Typical Forward Transconductance vs. I_D



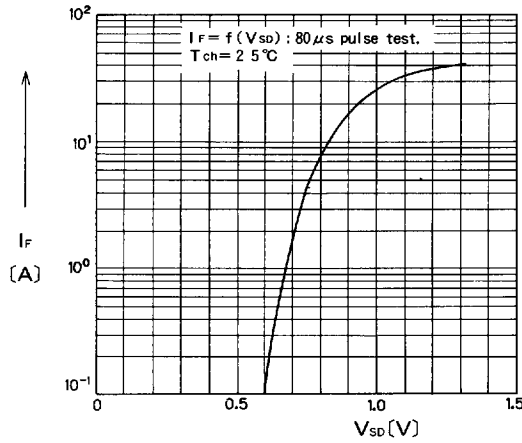
Gate Threshold Voltage vs. T_{ch}



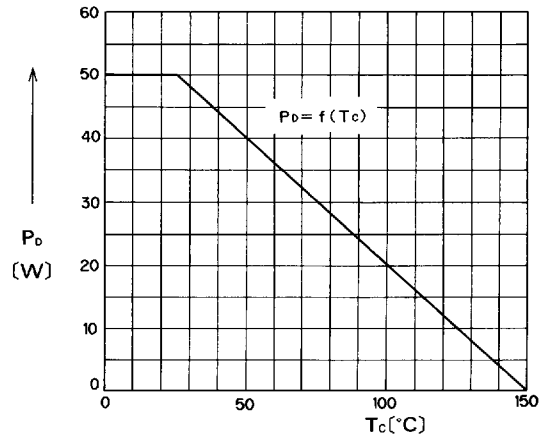
Typical Capacitance vs. V_{DS}



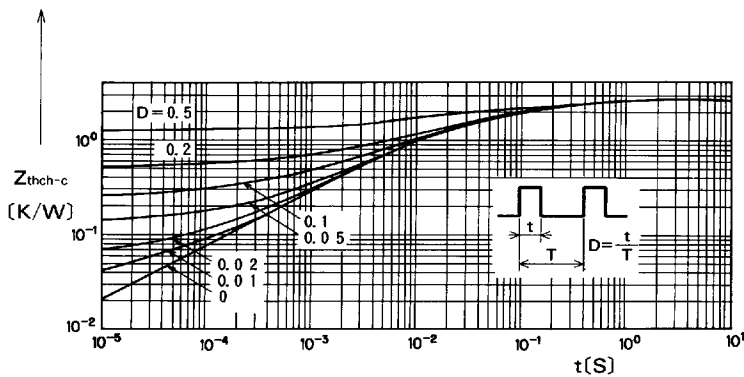
Typical Input Charge



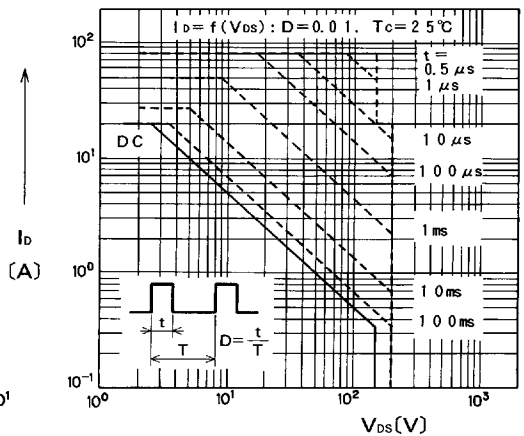
Forward Characteristics of Reverse Diode



Allowable Power Dissipation vs. T_c



Transient Thermal Impedance



Safe Operating Area